

Notice of References Cited	Application/Control No. 10/690,660	Applicant(s)/Patent Under Reexamination PARK, HEUI SEAG	
	Examiner Quang T Van	Art Unit 3742	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 03161911 A	07-1991	Japan	WATANABE et al.	H01F 27/00
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